

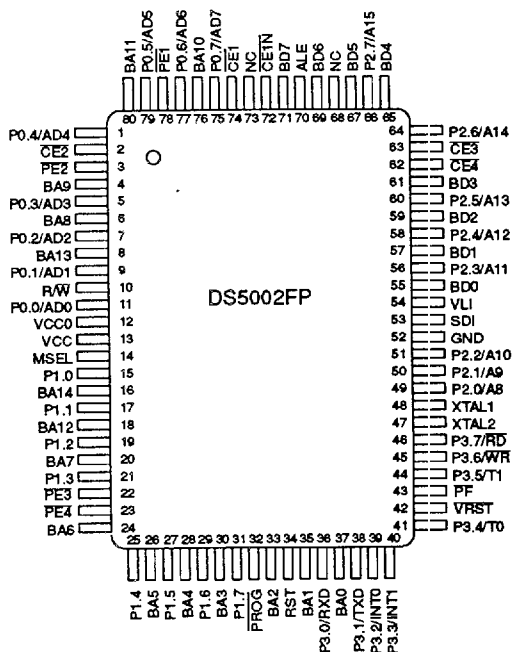
DALLAS SEMICONDUCTOR CORP

**DALLAS**  
SEMICONDUCTOR**DS5002FP**  
Secure Micro**FEATURES**

- 8051 compatible uC for secure/sensitive applications
  - Access 32, 64, or 128K bytes of nonvolatile SRAM for program and/or data storage
  - In-system programming via on-chip serial port
  - Capable of modifying its own program or data memory in the end system
- Firmware Security Features:
  - Memory stored in encrypted form
  - Encryption using on-chip 64-bit key
  - Automatic true random key generator
  - SDI Self Destruct Input
  - Top coating prevent microprobe
  - Improved security over previous generations
  - Protects memory contents from piracy
- Crashproof Operation
  - Maintains all nonvolatile resources for over 10 years in the absence of power
  - Power-fail Reset
  - Early Warning Power-fail Interrupt
  - Watchdog Timer

**DESCRIPTION**

The DS5002FP Secure Micro Chip is a secure version of the DS5001FP 128K Micro Chip. In addition to the memory and I/O enhancements of the DS5001FP, the Secure Micro Chip incorporates the most sophisticated security features available in any microcontroller. The security features of the DS5002FP include an array of mechanisms which are designed to resist all levels of threat, including observation, analysis, and physical attack. As a result, a massive effort would be required to obtain any information about memory contents. Furthermore, the "soft" nature of the DS5002FP allows frequent modification of the secure information, thereby minimizing the value of any secure information obtained by such a massive effort.

**PIN ASSIGNMENT**

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The Secure Micro Chip offers a number of major enhancements to the software security implemented in the previous generation DS5000. First, the DS5002FP provides a stronger software encryption algorithm which incorporates elements of DES encryption. Second, the encryption is based on a 64-bit key word, as compared to the DS5000's 40-bit key. Third, the key can only be loaded from an on-chip true random number generator. As a result, the true key value is never known by the user. Fourth, a Self-Destruct input pin (SDI) is provided to interface to external tamper detection circuitry. With or without the presence of  $V_{CC}$ , activation of the SDI pin has the same effect as resetting the Security Lock: immediate erasure of the key word and the 48-byte Vector RAM area. Fifth, a special top-coating of the die prevents access of information using microprobing techniques. Finally, customer-specific versions of the DS5002FP are available which incorporate a one-of-a-kind encryption algorithm.

When implemented as a part of a secure system design, a system based on the DS5002FP can typically provide a level of security which requires more time and resources to defeat than it is worth to unauthorized individuals who have reason to try.

**ORDERING INFORMATION**

The following versions of the DS5002FP are available as standard products from Dallas Semiconductor:

PART #	CLOCK	PACKAGE
DS5002FP-12	12 MHz	80-pin QFP
DS5002FP-16	16 MHz	80-pin QFP
DS5002FPM-12	12 MHz	80-pin QFP with metal
DS5002FPM-16	16 MHz	80-pin QFP with metal

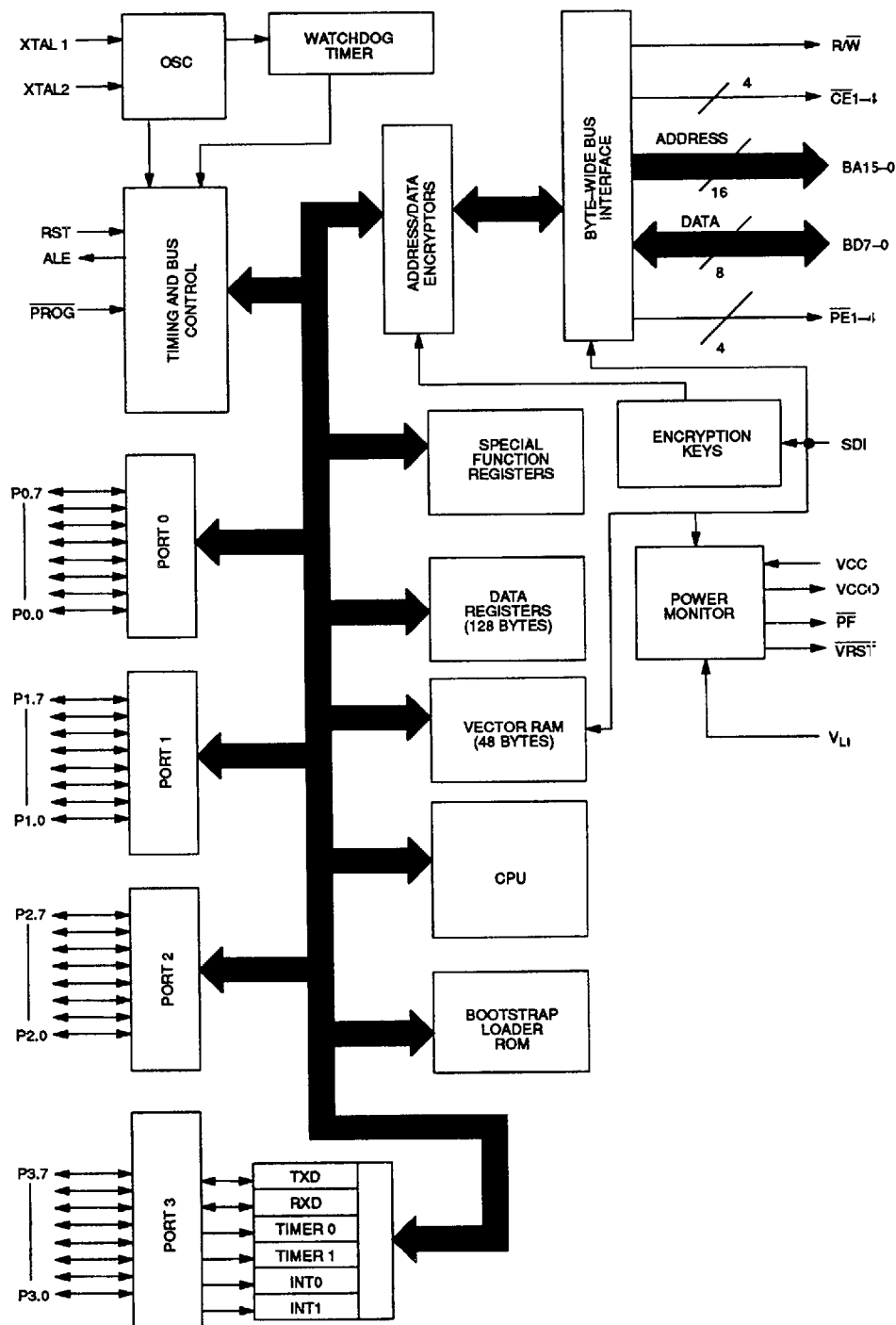
Please contact Dallas Semiconductor for ordering information on customer-specific versions of the DS5002FP.

**BLOCK DIAGRAM**

Figure 1 is a block diagram illustrating the internal architecture of the DS5002. The DS5002 is a secure implementation of the DS5001 128K Micro Chip. As a result, it operates in an identical fashion to the DS5001 except where indicated. See the DS5001 Data Sheet for operating details.

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DS5002 BLOCK DIAGRAM Figure 1



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## PIN DESCRIPTION

PIN NUMBER	DESCRIPTION
11, 9, 7, 5, 1, 79, 77, 75	P0.0–P0.7 General purpose I/O Port 0. This port is open-drain and can not drive a logic 1. It requires external pull-ups. Port 0 is also the multiplexed Expanded Address/Data bus. When used in this mode, it does not require pull-ups.
15, 17, 19, 21, 25, 27, 29, 31	P1.0 – P1.7 General purpose I/O Port 1.
49, 50, 51, 56, 58, 60, 64, 66	P2.0–P2.7 General purpose I/O Port 2. Also serves as the MSB of the Expanded Address bus.
36	P3.0 RXD General purpose I/O port pin 3.0. Also serves as the receive signal for the on board UART. This pin should <u>NOT</u> be connected directly to a PC COM port.
38	P3.1 TXD General purpose I/O port pin 3.1. Also serves as the transmit signal for the on board UART. This pin should <u>NOT</u> be connected directly to a PC COM port.
39	P3.2 $\overline{\text{INT0}}$ General purpose I/O port pin 3.2. Also serves as the active low External Interrupt 0.
40	P3.3 $\overline{\text{INT1}}$ General purpose I/O port pin 3.3. Also serves as the active low External Interrupt 1.
41	P3.4 T0 General purpose I/O port pin 3.4. Also serves as the Timer 0 input.
44	P3.5 T1 General purpose I/O port pin 3.5. Also serves as the Timer 1 input.
45	P3.6 $\overline{\text{WR}}$ General purpose I/O port pin. Also serves as the write strobe for Expanded bus operation.
46	P3.7 $\overline{\text{RD}}$ General purpose I/O port pin. Also serves as the read strobe for Expanded bus operation.
34	RST Active high reset input. A logic 1 applied to this pin will activate a reset state. This pin is pulled down internally so this pin can be left unconnected if not used. An RC power-on reset circuit is not needed and is <u>NOT</u> recommended.
70	ALE Address Latch Enable. Used to de-multiplex the multiplexed Expanded Address/Data bus on Port 0. This pin is normally connected to the clock input on a '373 type transparent latch.
47, 48	XTAL2, XTAL1 Used to connect an external crystal to the internal oscillator. XTAL1 is the input to an inverting amplifier and XTAL2 is the output.
52	GND Logic ground.
13	V <sub>CC</sub> +5V

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PIN NUMBER	DESCRIPTION
12	<b>V<sub>CCO</sub></b> V <sub>CC</sub> Output. This is switched between V <sub>CC</sub> and V <sub>LI</sub> by internal circuits based on the level of V <sub>CC</sub> . When power is above the lithium input, power will be drawn from V <sub>CC</sub> . The lithium cell remains isolated from a load. When V <sub>CC</sub> is below V <sub>LI</sub> , the V <sub>CCO</sub> switches to the V <sub>LI</sub> source. V <sub>CCO</sub> should be connected to the V <sub>CC</sub> pin of an SRAM.
54	<b>V<sub>LI</sub></b> Lithium Voltage Input. Connect to a lithium cell greater than V <sub>LImin</sub> and no greater than V <sub>LImax</sub> as shown in the electrical specifications. Nominal value is +3V.
16, 8, 18, 80, 76, 4, 6, 20, 24, 26, 28, 30, 33, 35, 37	<b>BA14-0</b> Byte-wide Address bus bits 14-0. This bus is combined with the non-multiplexed data bus (BD7-0) to access NVSRAM. Decoding is performed using CE1 through CE4. Therefore, BA15 is not actually needed. Read/write access is controlled by R/W. BA14-0 connect directly to an 8K, 32K, or 128K SRAM. If an 8K RAM is used, BA13 and BA14 will be unconnected. If a 128K SRAM is used, the micro converts CE2 and CE3 to serve as A16 and A15 respectively.
71, 69, 67, 65, 61, 59, 57, 55	<b>BD7-0</b> Byte-wide Data bus bits 7-0. This 8 bit bi-directional bus is combined with the non-multiplexed address bus (BA14-0) to access NVSRAM. Decoding is performed on CE1 and CE2. Read/write access is controlled by R/W. BD7-0 connect directly to an SRAM, and optionally to a Real-time Clock or other peripheral.
10	<b>R/W</b> Read/Write. This signal provides the write enable to the SRAMs on the Byte-wide bus. It is controlled by the memory map and Partition. The blocks selected as Program (ROM) will be write protected.
74	<b>CE1</b> Chip Enable 1. This is the primary decoded chip enable for memory access on the Byte-wide bus. It connects to the chip enable input of one SRAM. CE1 is lithium backed. It will remain in a logic high inactive state when V <sub>CC</sub> falls below V <sub>LI</sub> .
2	<b>CE2</b> Chip Enable 2. This chip enable is provided to access a second 32K block of memory. It connects to the chip enable input of one SRAM. When MSEL=0, the micro converts CE2 into A16 for a 128K x 8 SRAM. CE2 is lithium backed and will remain at a logic high when V <sub>CC</sub> falls below V <sub>LI</sub> .
63	<b>CE3</b> Chip Enable 3. This chip enable is provided to access a third 32K block of memory. It connects to the chip enable input of one SRAM. When MSEL=0, the micro converts CE3 into A15 for a 128K x 8 SRAM. CE3 is lithium backed and will remain at a logic high when V <sub>CC</sub> falls below V <sub>LI</sub> .
62	<b>CE4</b> Chip Enable 4. This chip enable is provided to access a fourth 32K block of memory. It connects to the chip enable input of one SRAM. When MSEL=0, this signal is unused. CE4 is lithium backed and will remain at a logic high when V <sub>CC</sub> falls below V <sub>LI</sub> .
78	<b>PE1</b> Peripheral Enable 1. Accesses data memory between addresses 0000h and 3FFFh when the PES bit is set to a logic 1. Commonly used to chip enable a Byte-wide real-time Clock such as the DS1283. PE1 is lithium backed and will remain at a logic high when V <sub>CC</sub> falls below V <sub>LI</sub> . Connect PE1 to battery backed functions only.

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PIN NUMBER	DESCRIPTION
3	<b>PE2</b> Peripheral Enable 2. Accesses data memory between addresses 4000h and 7FFFh when the PES bit is set to a logic 1. PE2 is lithium backed and will remain at a logic high when $V_{CC}$ falls below $V_{LI}$ . Connect PE2 to battery backed functions only.
22	<b>PE3</b> Peripheral Enable 3. Accesses data memory between addresses 8000h and BFFFh when the PES bit is set to a logic 1. PE3 is not lithium backed and can be connected to any type of peripheral function. If connected to a battery backed chip, it will need additional circuitry to maintain the chip enable in an inactive state when $V_{CC} < V_{LI}$ .
23	<b>PE4</b> Peripheral Enable 4. Accesses data memory between addresses C000h and FFFFh when the PES bit is set to a logic 1. PE4 is not lithium backed and can be connected to any type of peripheral function. If connected to a battery backed chip, it will need additional circuitry to maintain the chip enable in an inactive state when $V_{CC} < V_{LI}$ .
32	<b>PROG</b> Invokes the Bootstrap loader on a falling edge. This signal should be debounced so that only one edge is detected. If connected to ground, the micro will enter Bootstrap loading on power up. This signal is pulled up internally.
42	<b>VRST</b> This I/O pin indicates that the power supply ( $V_{CC}$ ) has fallen below the $V_{CCmin}$ level and the micro is in a reset state. When this occurs, the DS5002FP will drive this pin to a logic 0. Because the micro is lithium backed, this signal is guaranteed even when $V_{CC}=0V$ . Because it is an I/O pin, it will also force a reset if pulled low externally. This allows multiple parts to synchronize their power-down resets.
43	<b>PF</b> This output goes to a logic 0 to indicate that the micro has switched to lithium backup. This corresponds to $V_{CC} < V_{LI}$ . Because the micro is lithium backed, this signal is guaranteed even when $V_{CC}=0V$ . The normal application of this signal is to control lithium powered current to isolate battery backed functions from non-battery backed functions.
14	<b>MSEL</b> Memory select. This signal controls the memory size selection. When MSEL = +5V, the DS5002FP expects to use 32K x 8 SRAMs. When MSEL = 0V, the DS5002FP expects to use a 128K x 8 SRAM. MSEL must be connected regardless of Partition, Mode, etc.
53	<b>SDI</b> Self-Destruct Input. An active high on this pin causes an unlock procedure. This results in the destruction of Vector RAM, Encryption Keys, and the loss of power from $V_{CC0}$ . This pin should be grounded if not used.
72	<b>CE1N</b> This is a non-battery backed version of $\overline{CE1}$ . It is not generally useful since the DS5002 can not be used with EPROM due to its encryption.
73	<b>NC</b> Do not connect.

## SECURE OPERATION OVERVIEW

The DS5002FP incorporates encryption of the activity on its Byte-wide Address/Data bus to prevent unauthorized access to the program and data information contained in the nonvolatile RAM. Loading an application program in this manner is performed via the Bootstrap Loader using the general sequence described below:

1. Clear Security Lock
2. Set memory map configuration as for DS5001
3. Load application software
4. Set Security Lock
5. Exit Loader

Loading of application software into the program/data RAM is performed while the DS5002 is in its Bootstrap Load mode. Loading is only possible when the Security Lock is clear. If the Security Lock has previously set, then it must be cleared by issuing the "Z" command from the Bootstrap Loader. Resetting the security lock instantly clears the previous key word and the contents of the vector RAM. In addition, the Bootstrap ROM writes zeroes into the first 32K of external RAM.

The user's application software is loaded into external CMOS SRAM via the "L" command in "scrambled" form through on-chip encryptor circuits. Each external RAM address is an encrypted representation of an on-chip logical address. Thus, the sequential instructions of an ordinary program or data table are stored non-sequentially in RAM memory. The contents of the program/data RAM are also encrypted. Each byte in RAM is encrypted by a key- and address-dependent encryptor circuit such that identical bytes are stored as different values in different memory locations.

The encryption of the program/data RAM is dependent on an on-chip 64-bit key word. The key is loaded by the ROM firmware just prior to the time that the applica-

tion software is loaded, and is retained as nonvolatile information in the absence of  $V_{CC}$  by the lithium backup circuits. After loading is complete, the key is protected by setting the on-chip Security Lock, which is also retained as nonvolatile information in the absence of  $V_{CC}$ . Any attempt to tamper with the key word and thereby gain access to the true program/data RAM contents results in the erasure of the key word as well as the RAM contents.

During execution of the application software, logical addresses on the DS5002 that are generated from the program counter or data pointer registers are encrypted before they are presented on the Byte-wide Address Bus. Opcodes and data are read back and decrypted before they are operated on by the CPU. Similarly, data values written to the external nonvolatile RAM storage during program execution are encrypted before they are presented on the Byte-wide data bus during the write operation. This encryption/decryption process is performed in real time such that no execution time is lost as compared to the non-encrypted DS5001 or 8051 running at the same clock rate. As a result, operation of the encryptor circuitry is transparent to the application software.

Unlike the DS5000, the DS5002FP chip's security feature is always enabled.

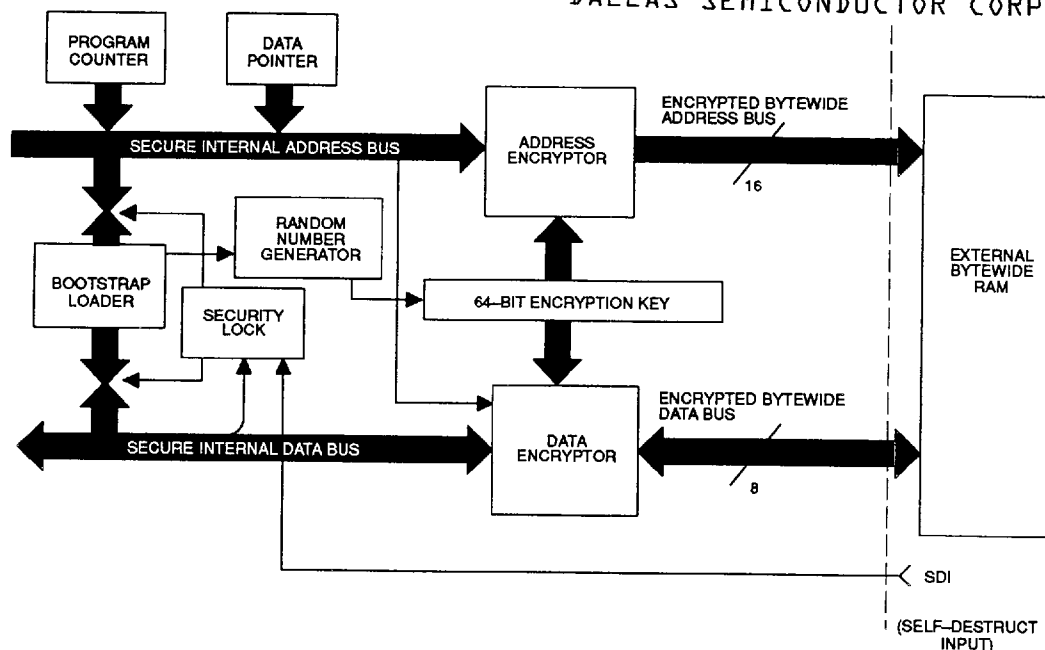
## SECURITY CIRCUITRY

The on-chip functions associated with the DS5002's software security feature are depicted in Figure 2. Encryption logic consists of an address encryptor and a data encryptor. Although each encryptor uses its own algorithm for encrypting data, both depend on the 64-bit key word which is contained in the encryption key registers. Both the encryptors operate during loading of the application software and also during its execution.

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DS5002 SECURITY CIRCUITRY Figure 2

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The address encryptor translates each "logical" address, i.e., the normal sequence of addresses that are generated in the logical flow of program execution, into an encrypted address (or "physical" address) at which the byte is actually stored. Each time a logical address is generated, either during program loading or during program execution, the address encryptor circuitry uses the value of the 64-bit key word and of the address itself to form the physical address which will be presented on the address lines of the RAM. The encryption algorithm is such that there is one and only one physical address for every possible logical address. The address encryptor operates over the entire memory range which is configured during Bootstrap Loading for access on the Byte-wide Bus.

As Bootstrap Loading of the application software is performed, the Data Encryptor logic transforms the opcode, operand, or data byte at any given memory location into an encrypted representation. As each byte is read back to the CPU during program execution, the internal Data Encryptor restores it to its original value. When a byte is written to the external nonvolatile program/data RAM during program execution, that byte is stored in encrypted form as well. The data encryption logic uses the value of the 64-bit key, the logical ad-

dress to which the data is being written, and the value of the data itself to form the encrypted data which is written to the nonvolatile program/data RAM. The encryption algorithm is repeatable, such that for a given data value, encryption key value, and logical address the encrypted byte will always be the same. However, there are many possible encrypted data values for each possible true data value due to the algorithm's dependency on the values of the logical address and encryption key.

When the application software is executed, the internal CPU of the DS5002 operates as normal. Logical addresses are calculated for opcode fetch cycles and also data read and write operations. The DS5002 has the ability to perform address encryption on logical addresses as they are generated internally during the normal course of program execution. In a similar fashion, data is manipulated by the CPU in its true representation. However, it is also encrypted when it is written to the external program/data RAM, and is restored to its original value when it is read back.

When an application program is stored in the format described above, it is virtually impossible to disassemble opcodes or to convert data back into its true representation. Address encryption has the effect that the op-



codes and data are not stored in the contiguous form in which they were assembled, but rather in seemingly random locations in memory. This in itself makes it virtually impossible to determine the normal flow of the program. As an added protection measure, the Address Encryptor also generates "dummy" read access cycles whenever time is available during program execution.

### DUMMY READ CYCLES

Like the DS5000, the DS5002FP generates a "dummy" read access cycle to non-sequential addresses in external RAM memory whenever time is available during program execution. This action has the effect of further complicating the task of determining the normal flow of program execution. During these pseudo-random dummy cycles, the RAM is read to all appearance, but the data is not used internally. Through the use of a repeatable exchange of dummy and true read cycles, it is impossible to distinguish a dummy cycle from a real one.

### ENCRYPTION ALGORITHM

The DS5002FP incorporates a proprietary algorithm implemented in hardware which performs the scrambling of address and data on the byte-wide bus to the static RAM. This algorithm has been greatly strengthened with respect to its DS5000 predecessor. Improvements include:

1. 64-bit encryption key
2. Incorporation of DES-like operations to provide a greater degree of nonlinearity.
3. Customizable encryption

The encryption circuitry uses a 64-bit key value (compared to the DS5000's 40-bit key) which is stored on the DS5002 die and protected by the Security Lock function described below. In addition, the algorithm has been strengthened to incorporate certain operations used in DES encryption, so that the encryption of both the addresses and data is highly nonlinear. Unlike the DS5000, the encryption circuitry in the DS5002 is always enabled.

Dallas Semiconductor can customize the encryption circuitry by laser programming the die to insure that a unique encryption algorithm is delivered to the customer. In addition, the customer-specific version can be branded as specified by the customer. Please contact

Dallas Semiconductor for ordering information of customer-specific versions.

### ENCRYPTION KEY

As described above, the on-chip 64-bit Encryption Key is the basis of both the address and data encryptor circuits. The DS5002 provides a key management system which is greatly improved over the DS5000. The DS5002 does not give the user the ability to select a key. Instead, when the loader is given certain commands, the key is set based on the value read from an on-chip hardware random number generator. This action is performed just prior to actually loading the code into the external RAM. This scheme prevents characterization of the encryption algorithm by continuously loading new, known keys. It also frees the user from the burden of protecting the key selection process.

The random number generator circuit uses the asynchronous frequency differences of two internal ring oscillator and the processor master clock (determined by XTAL1 and XTAL2). As a result, a true random number is produced.

### VECTOR RAM

A 48-byte vector RAM area is incorporated on-chip, and is used to contain the reset and interrupt vector code in the DS5002. It is included in the architecture to help insure the security of the application program.

If reset and interrupt vector locations were accessed from the external nonvolatile program/data RAM during the execution of the program, then it would be possible to determine the encrypted value of known addresses. This could be done by forcing an interrupt or reset condition and observing the resulting addresses on the Byte-wide address/data bus. For example, it is known that when a hardware reset is applied the logical program address is forced to location 0000H and code is executed starting from this location. It would then be possible to determine the encrypted value (or physical address) of the logical address value 0000H by observing the address presented to the external RAM following a hardware reset. Interrupt vector address relationships could be determined in a similar fashion. By using the on-chip vector RAM to contain the interrupt and reset vectors, it is impossible to observe such relationships. Although it is very unlikely that an application program could be deciphered by observing vector address rela-

tionships, the vector RAM eliminates this possibility. Note that the dummy accesses mentioned above are conducted while fetching from vector RAM.

The Vector RAM is automatically loaded with the user's reset and interrupt vectors during bootstrap loading.

### SECURITY LOCK

Once the application program has been loaded into the DS5002's NVRAM, the Security Lock may be enabled by issuing the "Z" command in the Bootstrap Loader. While the Security Lock is set, no further access to program/data information is possible via the on-chip ROM. Access is prevented by both the bootstrap loader firmware and the DS5002FP encryptor circuits.

Access to the NVRAM may only be regained by clearing the Security Lock via the "U" command in the Bootstrap Loader. This action triggers several events which defeat tampering. First, the encryption key is instantaneously erased. Without the encryption key, the DS5002FP is no longer able to decrypt the contents of the RAM. Therefore, the application software can no longer be correctly executed, nor can it be read back in its true form via the Bootstrap Loader. Second, the Vector RAM area is also instantaneously erased, so that the reset and vector information is lost. Third, the Bootstrap Loader firmware sequentially erases the encrypted RAM area. Lastly, the loader creates and loads a new random key.

The Security Lock bit itself is constructed using a multiple-bit latch which is interlaced for self-destruct in the event of tampering. The lock is designed to set-up a "domino-effect" such that erasure of the bit will result in an unstoppable sequence of events that clears critical data including encryption key and vector RAM. In addition, this bit is protected from probing by the top-coating feature mentioned below.

### SELF-DESTRUCT INPUT

The Self-Destruct Input (SDI) pin is an active high input which is used to reset the Security Lock in response to an external event. The SDI input is intended to be used with external tamper detection circuitry. It can be activated with or without operating power applied to the V<sub>CC</sub>

pin. Activation of the SDI pin instantly resets the security lock and causes the same sequence of events described above for this action. In addition, power is momentarily removed from the Byte-wide bus interface including the V<sub>CCO</sub> pin, resulting in the loss of data in external RAM.

### TOP LAYER COATING

The DS5002 is provided with a special top-layer coating that is designed to prevent a probe attack. This coating is implemented with second-layer metal added through special processing of the microcontroller die. This additional layer is not a simple sheet of metal, but rather a complex layout that is interwoven with power and ground which are in turn connected to logic for the Encryption Key and the Security Lock. As a result, any attempt to remove the layer or probe through it will result in the erasure of the security lock and/or the loss of encryption key bits.

### BOOTSTRAP LOADING

Initial loading of application software into the DS5002 is performed by firmware within the on-chip Bootstrap Loader communicating with a PC via the on-chip serial port in a manner which is almost identical to that for the DS5001. The user should consult the DS5001 data sheet as a basis of operational characteristics of this firmware. Certain differences in loading procedure exist in order to support the security feature. These differences are documented below. Table 1 summarizes the commands accepted by the bootstrap loader.

When the Bootstrap Loader is invoked, the 128-byte scratchpad RAM area is automatically overwritten with zeroes, and then used for variable storage for the bootstrap firmware. Also, a set of 8 bytes are generated using the random number generator circuitry and are saved as a potential word for the 64-bit encryption key.

Any read or write operation to the DS5002's external program/data SRAM can only take place if the Security Lock bit is in a cleared state. Therefore, the first step which is taken in the loading of a program should be the clearing of the Security Lock bit through the "U" command.

DS5002 SERIAL BOOTSTRAP LOADER COMMANDS Table 1

COMMAND	FUNCTION
C	Return CRC—16 of the program/data NVRAM
D	Dump Intel Hex file
F	Fill program/data NVRAM
G	Get Data from P1, P2, and P3
I	N/A on the DS5002FP
L	Load Intel Hex file
M	Toggle modem available bit
N	Set Freshness Seal - All program and data will be lost
P	Put data into P0, P1, P2, and P3
R	Read status of NVSFRs (MCON, RPCTL, MSL, CALIB)
T	Trace (echo) incoming Intel Hex code
U	Clear security lock
V	Verify program/data NVRAM with incoming Intel Hex data
W	Write Special Function Registers - (MCON, RPCTL, MSL, CALIB)
Z	Set security lock

Execution of certain bootstrap loader commands will result in the loading of the newly generated 64-bit random number into the encryption key word. These commands are as follows:

- a. Fill F
- b. Load L
- c. Dump D
- d. Verify V
- e. CRC C

Execution of the Fill and Load commands will result in the data loaded into the NVRAM in an encrypted form determined by the value of the newly-generated key word. The subsequent execution of the Dump command within the same bootstrap session will cause the contents of the encrypted RAM to be read out and transmitted back to the host PC in decrypted form. Similarly, execution of the Verify command within the same bootstrap session will cause the incoming absolute hex data to be compared against the true contents of the encrypted RAM, and the CRC command will return the CRC value calculated from the true contents of the encrypted RAM. As long as any of the above commands are executed within the same bootstrap session, the

loaded key value will remain the same and contents of the encrypted program/data NVRAM may be read or written normally and freely until the Security Lock bit is set.

When the Security Lock bit is set using the Z command, no further access to the true RAM contents is possible using any bootstrap command or by any other means.

### INSTRUCTION SET

The DS5002FP executes an instruction set that is object code compatible with the industry standard 8051 microcontroller. As a result, software development packages such as assemblers and compilers that have been written for the 8051 are compatible with the DS5002FP. A complete description of the instruction set and operation are provided in the User's Guide section of the Soft Microcontroller Data Book.

Also note that the DS5002FP is embodied in the DS2252(T) module. The DS2252(T) combines the DS5002FP with between 32K and 128K of SRAM, and a lithium cell. An optional Real-time Clock is also available in the DS2252T. This is packaged in a 40-pin SIMM module.

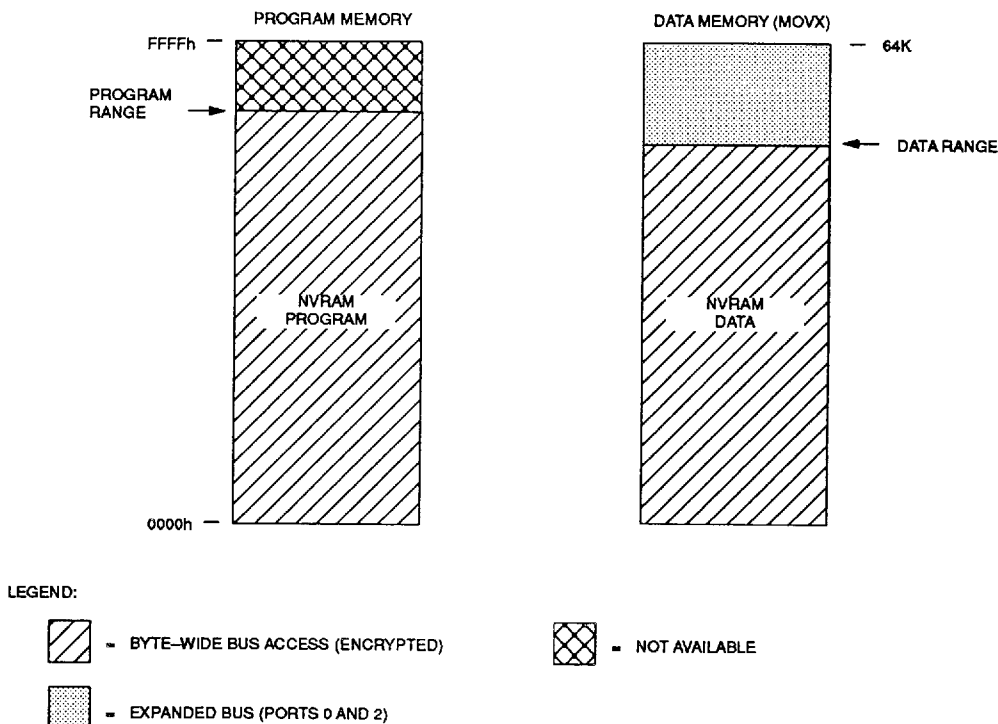
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## MEMORY ORGANIZATION

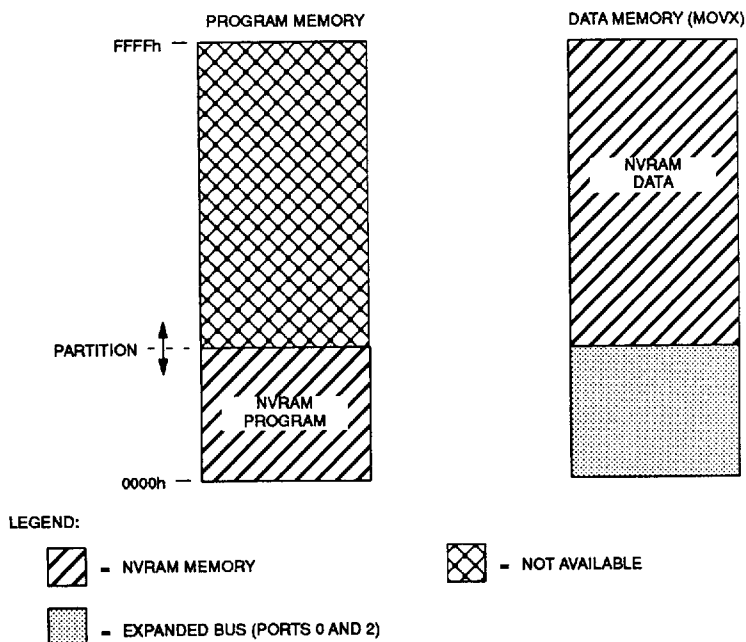
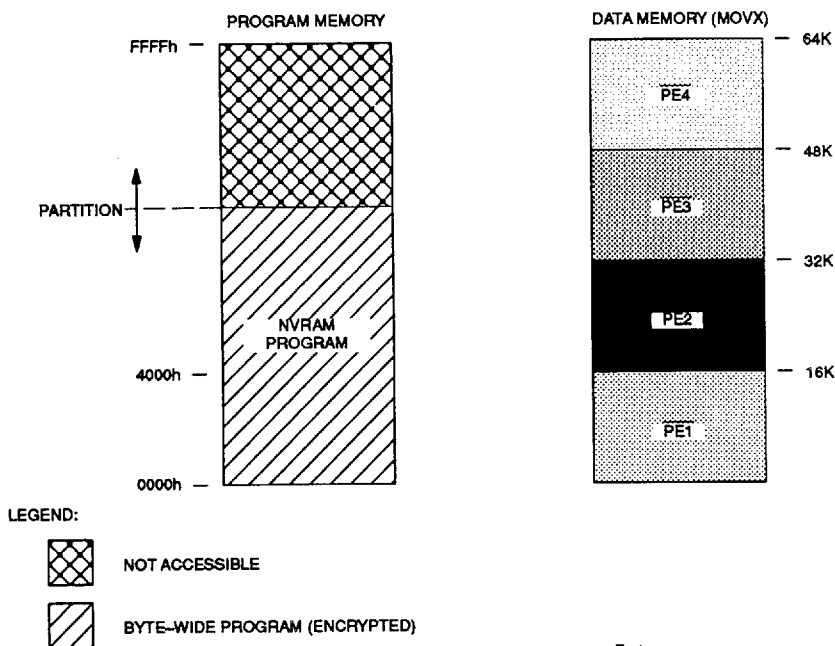
Figure 3 illustrates the memory map accessed by the DS5002FP. The entire 64K of program and 64K of data are potentially available to the Byte-wide bus. This preserves the I/O ports for application use. The user controls the portion of memory that is actually mapped to the Byte-wide bus by selecting the Program Range and Data Range. Any area not mapped into the NVRAM is reached via the Expanded bus on Ports 0 & 2. An alter-

nate configuration allows dynamic Partitioning of a 64K space as shown in Figure 4. Selecting PES=1 provides another 64K of potential data storage or memory mapped peripheral space as shown in Figure 5. These selections are made using Special Function Registers. The memory map and its controls are covered in detail in the User's Guide section of the Soft Microcontroller Data Book.

**MEMORY MAP OF THE DS5002FP WITH PM=1** Figure 3



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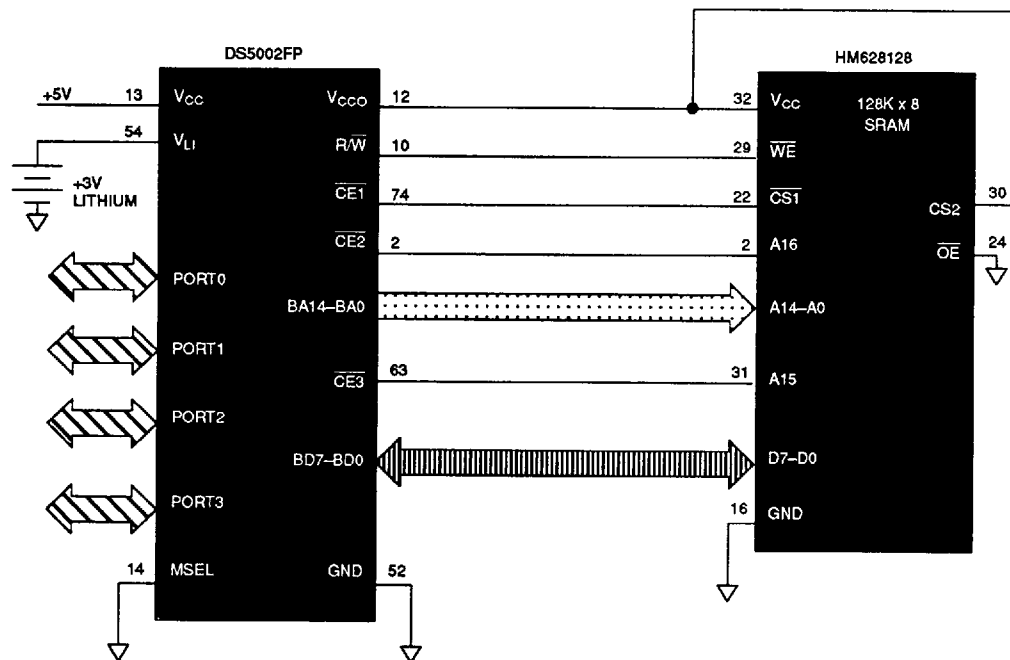
**MEMORY MAP OF THE DS5002FP WITH PM=0 Figure 4****MEMORY MAP OF THE DS5002FP WITH PES=1 Figure 5**

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Figure 6 illustrates a typical memory connection for a system using a 128K byte SRAM. Note that in this configuration, both program and data are stored in a common RAM chip. Figure 7 shows a similar system with

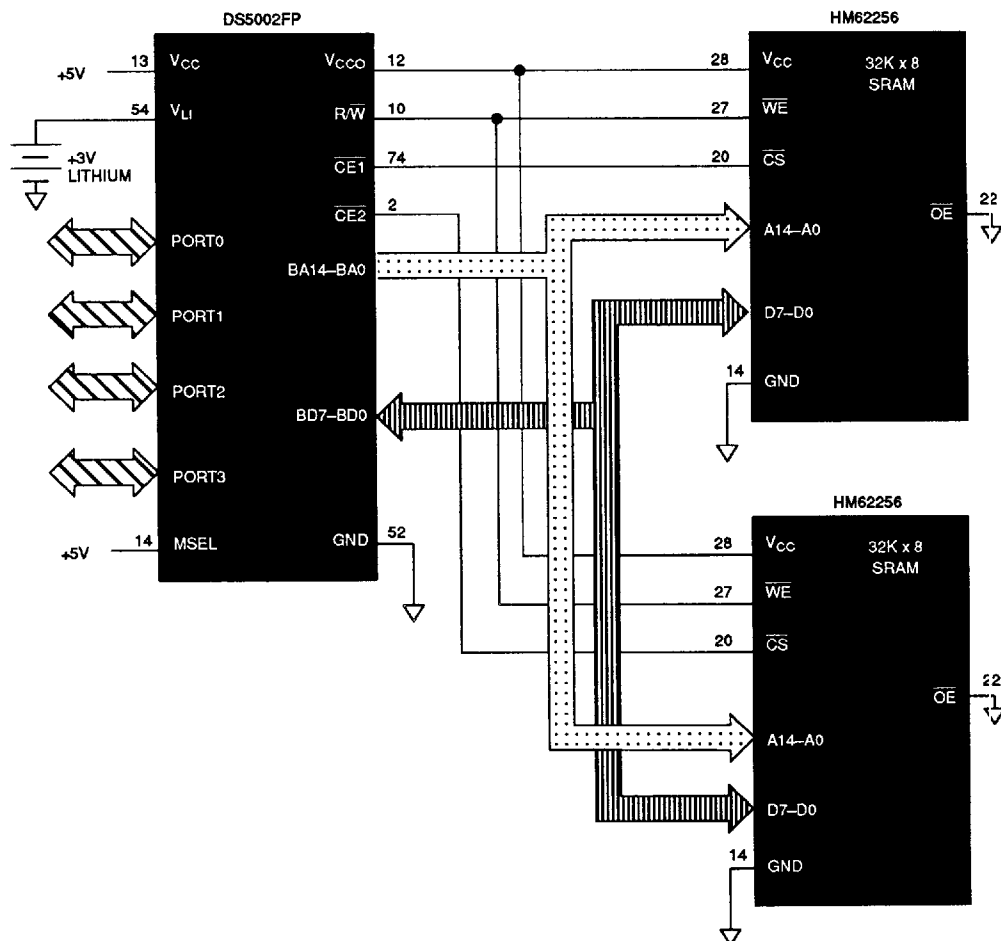
using two 32K byte SRAMs. The Byte-wide Address bus connects to the SRAM address lines. The bi-directional Byte-wide data bus connects the data I/O lines of the SRAM.

**DS5002FP CONNECTION TO 128K X 8 SRAM** Figure 6



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## DS5002FP CONNECTION TO 64K X 8 SRAM Figure 7



## POWER MANAGEMENT

The DS5002FP monitors  $V_{CC}$  to provide Power-fail Reset, early warning Power-fail Interrupt, and switch over to lithium backup. It uses an internal band-gap reference in determining the switch points. These are called  $V_{PFW}$ ,  $V_{CCMIN}$ , and  $V_{LI}$  respectively. When  $V_{CC}$  drops below  $V_{PFW}$ , the DS5002FP will perform an interrupt vector to location 2Bh if the power fail warning was enabled. Full processor operation continues regardless. When power falls further to  $V_{CCMIN}$ , the DS5002FP invokes a reset state. No further code execution will be performed unless power rises back above  $V_{CCMIN}$ . All decoded chip enables and the  $R/\overline{W}$  signal go to an inactive (logic 1) state.  $V_{CC}$  is still the power source at this time. When  $V_{CC}$  drops further to

below  $V_{LI}$ , internal circuitry will switch to the lithium cell for power. The majority of internal circuits will be disabled and the remaining nonvolatile states will be retained. Any devices connected to  $V_{CCO}$  will be powered by the lithium cell at this time.  $V_{CCO}$  will be at the lithium battery voltage less a diode drop. This drop will vary depending on the load. Low power SRAMs should be used for this reason. When using the DS5002FP, the user must select the appropriate battery to match the RAM data retention current and the desired backup lifetime. Note that the lithium cell is only loaded when  $V_{CC} < V_{LI}$ . The User's Guide has more information on this topic. The trip points  $V_{CCMIN}$  and  $V_{PFW}$  are listed in the electrical specifications.

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**ELECTRICAL SPECIFICATIONS**

The DS5002FP adheres to all AC and DC electrical specifications published for the DS5001FP. The absolute

maximum ratings and unique specifications for the DS5002FP are listed below.

**ABSOLUTE MAXIMUM RATINGS\***

Voltage on Any Pin Relative to Ground

−0.3V to 7.0V

Operating Temperature

0°C to +70°C

Storage Temperature

−40°C to 70°C

Soldering Temperature

260°C for 10 seconds

\* This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operation sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods of time may affect reliability.

**DC CHARACTERISTICS**

( $t_A=0^\circ\text{C}$  to  $70^\circ\text{C}$ ;  $V_{CC}=5V \pm 10\%$ )

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
Input Low Voltage	$V_{IL}$	−0.3		0.8	V	1
Input High Voltage	$V_{IH1}$	2.0		$V_{CC}+0.3$	V	1
Input High Voltage (RST, XTAL1, PROG)	$V_{IH2}$	3.5		$V_{CC}+0.3$	V	1
Output Low Voltage @ $I_{OL}=1.6\text{ mA}$ (Ports 1, 2, 3)	$V_{OL1}$		0.15	0.45	V	1
Output Low Voltage @ $I_{OL}=3.2\text{ mA}$ (Port 0, ALE, PF, BA15−0, BD7−0, R/W, CE1N, CE1−4, PE1−4)	$V_{OL2}$		0.15	0.45	V	1
Output High Voltage @ $I_{OH}=80\text{ mA}$ (Ports 1, 2, 3)	$V_{OH1}$	2.4	4.8		V	1
Output High Voltage @ $I_{OH}=400\text{ }\mu\text{A}$ (Ports 0, ALE, PF, BA15−0, BD7−0, R/W, CE1N, CE1−4, PE1−4)	$V_{OH2}$	2.4	4.8		V	1
Input Low Current $V_{IN}=0.45V$ (Ports 1, 2, 3)	$I_{IL}$			−50	$\mu\text{A}$	
Transition Current; 1 to 0 $V_{IN}=2.0V$ (Ports 1, 2, 3)	$I_{TL}$			−500	$\mu\text{A}$	
SDI Input Low Voltage	$V_{ILS}$			0.4	V	1
SDI Input High Voltage	$V_{IHS}$	2.0		$V_{CC0}$	V	1
SDI Pull-Down Resistor	$R_{SDI}$	25		60	$K\Omega$	
Battery-Backup Quiescent Current	$I_{BAT}$		5	75	nA	7

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**DC CHARACTERISTICS (cont'd)** $(t_A=0^{\circ}\text{C to }70^{\circ}\text{C}; V_{CC}=5\text{V} \pm 10\%)$ 

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
Input Leakage Current $0.45 < V_{IN}, V_{CC}$ (Port 0, MSEL)	$I_{IL}$			$\pm 10$	$\mu\text{A}$	
RST Pulldown Resistor	$R_{RE}$	40		150	$\text{K}\Omega$	
VRST Pullup Resistor	$R_{VR}$		4.7		$\text{K}\Omega$	
PROG Pullup Resistor	$R_{PR}$		40		$\text{K}\Omega$	
Power Fail Warning Voltage	$V_{PRW}$	4.25	4.37	4.50	V	1
Minimum Operating Voltage	$V_{CCMIN}$	4.00	4.12	4.25	V	1
Lithium Supply Voltage	$V_{IL}$	2.5		4.0	V	1
Operating Current	$I_{CC}$			36	mA	2
Idle Mode Current	$I_{IDLE}$			7.0	mA	3
Stop Mode Current	$I_{STOP}$			80	$\mu\text{A}$	4
Pin Capacitance	$C_{IN}$			10	pF	5
Output Supply Voltage ( $V_{CCO}$ )	$V_{CCO1}$			$V_{CC}-0.3$	V	1, 2
Output Supply Battery-backed Mode ( $V_{CCO}$ , CE1-4, PE1-2)	$V_{CCO2}$			$V_{LI}-0.55$	V	1, 8
Output Supply Current @ $V_{CCO}=V_{CC}-0.3\text{V}$	$I_{CCO1}$			75	mA	6
Lithium-backed Quiescent Current	$I_{LI}$		5	75	nA	7
Reset Trip Point in Stop Mode w/BAT=3.0V w/BAT=3.3V		4.0 4.4		4.25 4.65		1

**AC CHARACTERISTICS** $(t_A=0^{\circ}\text{C to }70^{\circ}\text{C}; V_{CC}=0\text{V to }5\text{V})$ 

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
SDI Pulse Reject	$t_{SPR}$			2	us	10
SDI Pulse Accept	$t_{SPA}$	10			us	10

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## DALLAS SEMICONDUCTOR CORP

## AC CHARACTERISTICS

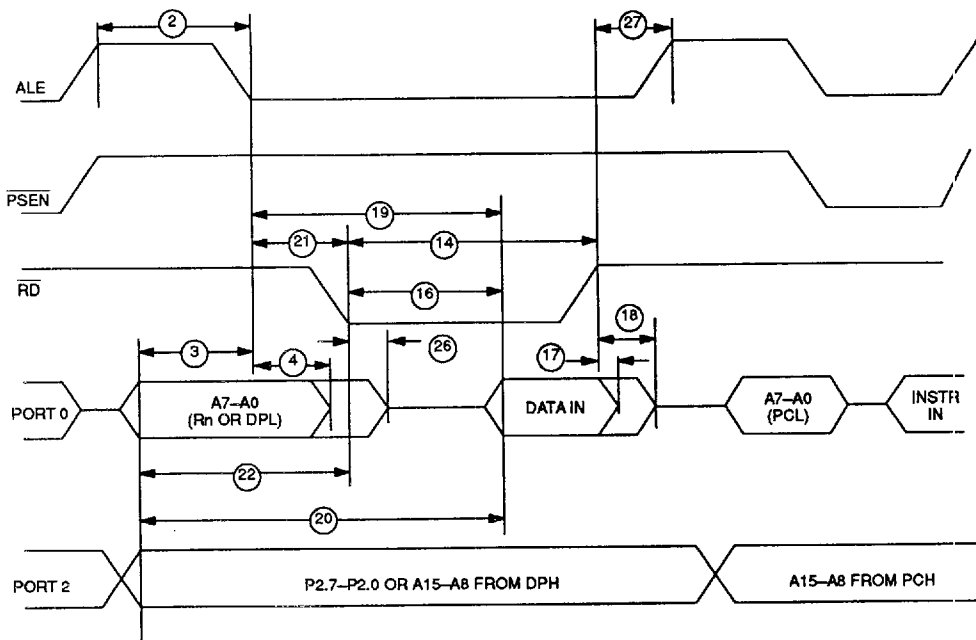
## EXPANDED BUS MODE TIMING SPECIFICATIONS

(t<sub>A</sub>=0°C to 70°C; V<sub>CC</sub>=5V ± 10%)

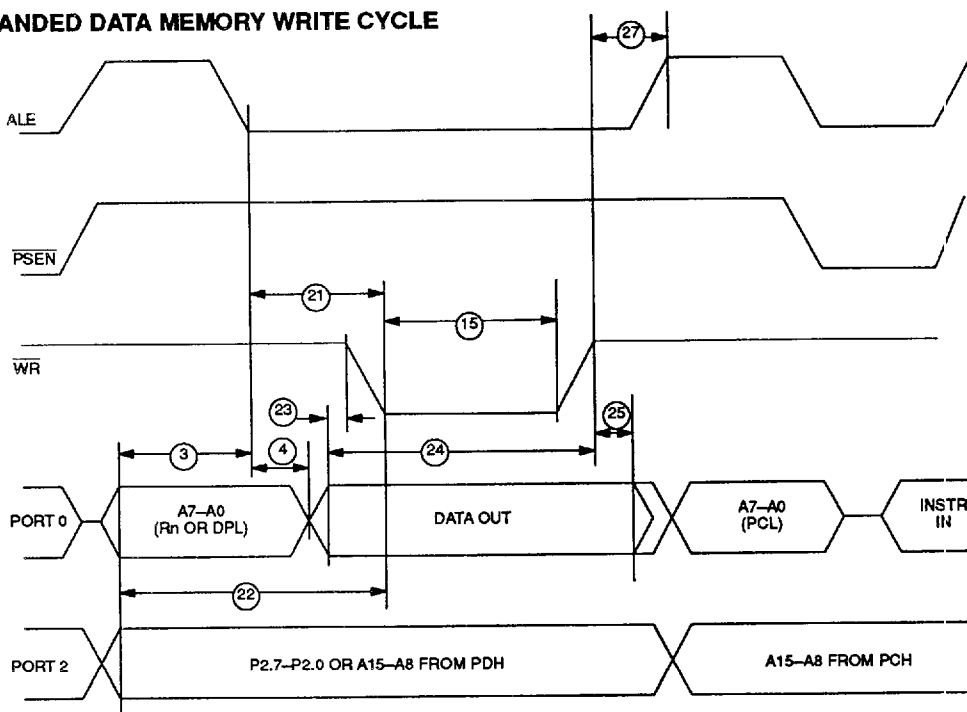
#	PARAMETER	SYMBOL	MIN	MAX	UNITS
1	Oscillator Frequency	1/t <sub>CLK</sub>	1.0	12 (-12) 16 (-16)	MHz
2	ALE Pulse Width	t <sub>ALPW</sub>	2t <sub>CLK</sub> -40		ns
3	Address Valid to ALE Low	t <sub>AVALL</sub>	t <sub>CLK</sub> -40		ns
4	Address Hold After ALE Low	t <sub>AAVAV</sub>	t <sub>CLK</sub> -35		ns
14	$\overline{RD}$ Pulse Width	t <sub>RD PW</sub>	6t <sub>CLK</sub> -100		ns
15	$\overline{WR}$ Pulse Width	t <sub>WR PW</sub>	6t <sub>CLK</sub> -100		ns
16	$\overline{RD}$ Low to Valid Data In @12 MHz @16 MHz	t <sub>RDL DV</sub>		5t <sub>CLK</sub> -165 5t <sub>CLK</sub> -105	ns ns
17	Data Hold after $\overline{RD}$ High	t <sub>RD HDV</sub>	0		ns
18	Data Float after $\overline{RD}$ High	t <sub>RD HDZ</sub>		2t <sub>CLK</sub> -70	ns
19	ALE Low to Valid Data In @12 MHz @16 MHz	t <sub>ALL VD</sub>		8t <sub>CLK</sub> -150 8t <sub>CLK</sub> -90	ns ns
20	Valid Addr. to Valid Data In @12 MHz @16 MHz	t <sub>AV DV</sub>		9t <sub>CLK</sub> -165 9t <sub>CLK</sub> -105	ns ns
21	ALE Low to $\overline{RD}$ or $\overline{WR}$ Low	t <sub>ALL RDL</sub>	3t <sub>CLK</sub> -50	3t <sub>CLK</sub> +50	ns
22	Address Valid to $\overline{RD}$ or $\overline{WR}$ Low	t <sub>AV RDL</sub>	4t <sub>CLK</sub> -130		ns
23	Data Valid to $\overline{WR}$ Going Low	t <sub>DV WRL</sub>	t <sub>CLK</sub> -60		ns
24	Data Valid to $\overline{WR}$ High @12 MHz @16 MHz	t <sub>DV WRH</sub>	7t <sub>CLK</sub> -150 7t <sub>CLK</sub> -90		ns ns
25	Data Valid after $\overline{WR}$ High	t <sub>WR HDV</sub>	t <sub>CLK</sub> -50		ns
26	$\overline{RD}$ Low to Address Float	t <sub>RDL AZ</sub>		0	ns
27	$\overline{RD}$ or $\overline{WR}$ High to ALE High	t <sub>RDL ALH</sub>	t <sub>CLK</sub> -40	t <sub>CLK</sub> +50	ns

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## EXPANDED DATA MEMORY READ CYCLE



## EXPANDED DATA MEMORY WRITE CYCLE



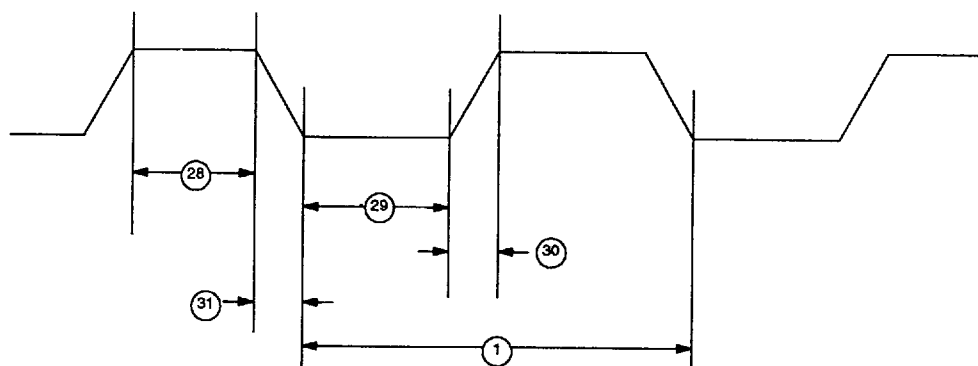
**AC CHARACTERISTICS (cont'd)**  
**EXTERNAL CLOCK DRIVE**

DALLAS SEMICONDUCTOR CORP.

( $t_A = 0^\circ\text{C}$  to  $70^\circ\text{C}$ ;  $V_{CC} = 5V \pm 10\%$ )

#	PARAMETER	SYMBOL	MIN	MAX	UNITS
28	External Clock High Time @12 MHz @16 MHz	$t_{CLKHPW}$	20 15		ns ns
29	External Clock Low Time @12 MHz @16 MHz	$t_{CLKLPW}$	20 15		ns ns
30	External Clock Rise Time @12 MHz @16 MHz	$t_{CLKR}$		20 15	ns ns
31	External Clock Fall Time @12 MHz @16 MHz	$t_{CLKF}$		20 15	ns ns

**EXTERNAL CLOCK TIMING**



## DALLAS SEMICONDUCTOR CORP

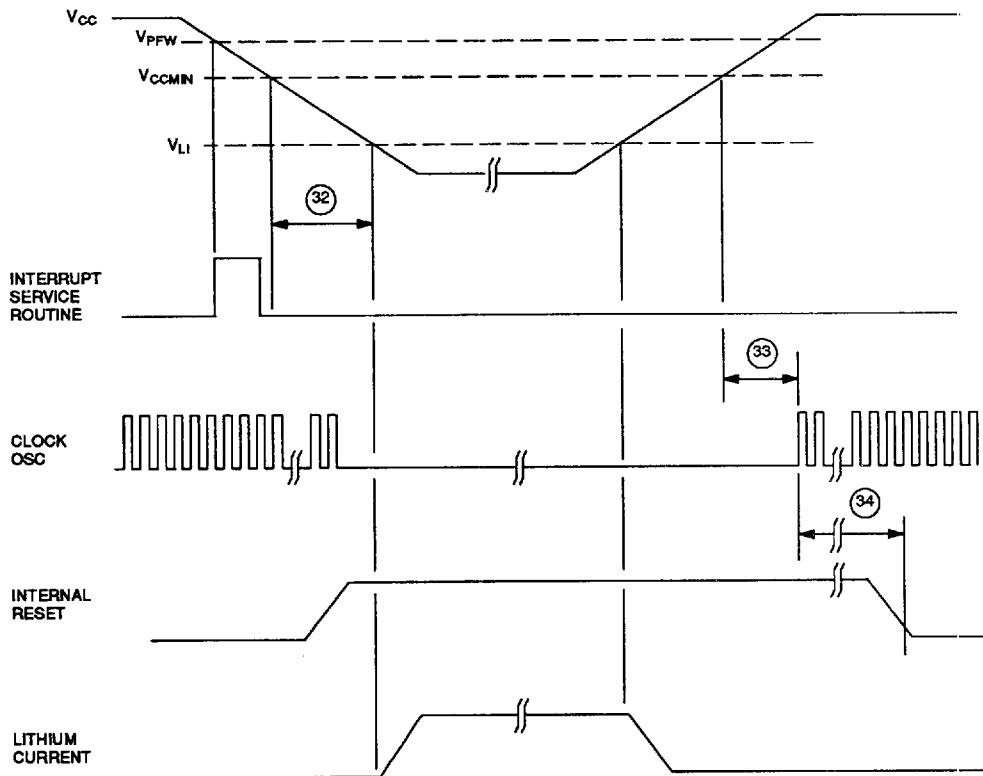
## AC CHARACTERISTICS (cont'd)

## POWER CYCLING TIMING

 $(t_A = 0^\circ\text{C to } 70^\circ\text{C}; V_{CC} = 5V \pm 10\%)$ 

#	PARAMETER	SYMBOL	MIN	MAX	UNITS
32	Slew Rate from $V_{CCmin}$ to $V_{LI}$	$t_F$	130		$\mu\text{s}$
33	Crystal Start up Time	$t_{CSU}$		(note 9)	
34	Power On Reset Delay	$t_{POR}$		21504	$t_{CLK}$

## POWER CYCLE TIMING

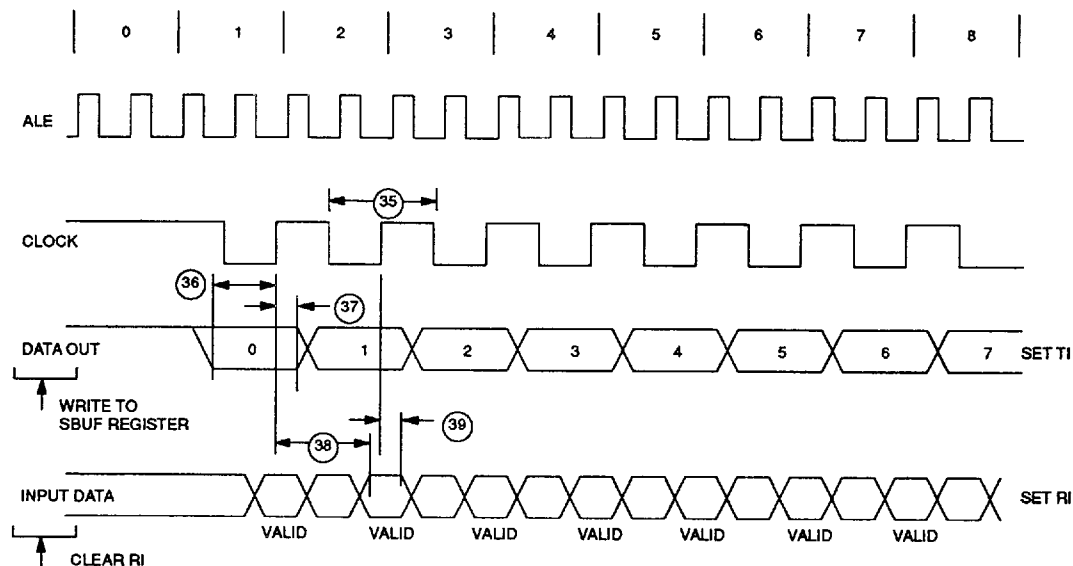


**AC CHARACTERISTICS (cont'd)**  
**SERIAL PORT TIMING – MODE 0**

DALLAS SEMICONDUCTOR CORP

(t<sub>A</sub> = 0°C to 70°C; V<sub>CC</sub> = 5V ± 10%)

#	PARAMETER	SYMBOL	MIN	MAX	UNITS
35	Serial Port Clock Cycle Time	t <sub>SPCLK</sub>	12t <sub>CLK</sub>		μs
36	Output Data Setup to Rising Clock Edge	t <sub>DOCH</sub>	10t <sub>CLK</sub> -133		ns
37	Output Data Hold after Rising Clock Edge	t <sub>CHDO</sub>	2t <sub>CLK</sub> -117		ns
38	Clock Rising Edge to Input Data Valid	t <sub>CHDV</sub>		10t <sub>CLK</sub> -133	ns
39	Input Data Hold after Rising Clock Edge	t <sub>CHDIV</sub>	0		ns

**SERIAL PORT TIMING – MODE 0**


## DALLAS SEMICONDUCTOR CORP

## AC CHARACTERISTICS

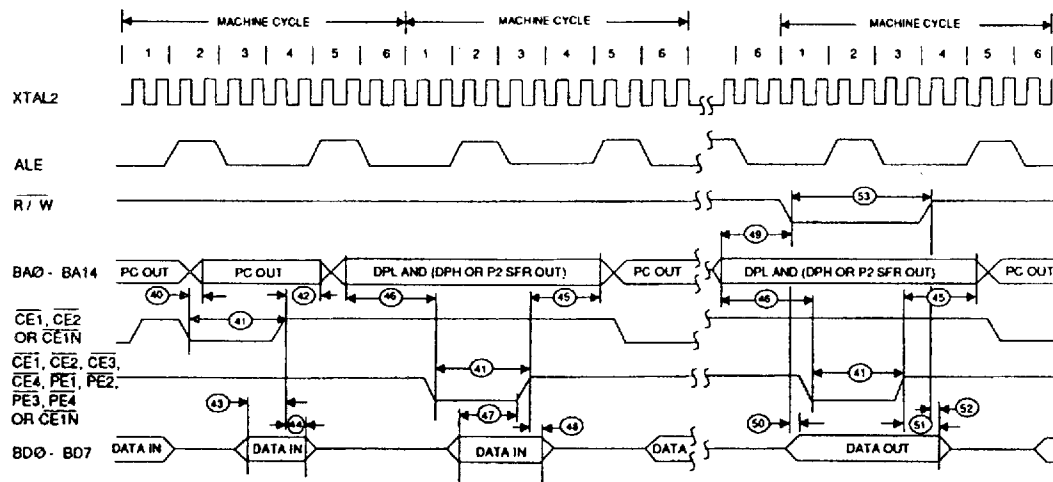
## BYTEWIDE ADDRESS/DATA BUS TIMING

(t<sub>A</sub> = 0°C to 70°C; V<sub>CC</sub> = 5V ± 10%)

#	PARAMETER	SYMBOL	MIN	MAX	UNITS
40	Delay to Byte-wide Address Valid from CE1, CE2 or CE1N Low During Opcode Fetch	t <sub>CE1LPA</sub>		30	ns
41	Pulse Width of $\overline{\text{CE1-4}}$ , $\overline{\text{PE1-4}}$ or $\overline{\text{CE1N}}$	t <sub>CEPW</sub>	4t <sub>CLK</sub> -35		ns
42	Byte-wide Address Hold After CE1, CE2 or CE1N High During Opcode Fetch	t <sub>CE1HPA</sub>	2t <sub>CLK</sub> -20		ns
43	Byte-wide Data Setup to $\overline{\text{CE1}}$ , CE2 or CE1N High During Opcode Fetch	t <sub>OVCE1H</sub>	1t <sub>CLK</sub> +40		ns
44	Byte-wide Data Hold After $\overline{\text{CE1}}$ , $\overline{\text{CE2}}$ or CE1N High During Opcode Fetch	t <sub>CE1HOV</sub>	10		ns
45	Byte-wide Address Hold After $\overline{\text{CE1-4}}$ , $\overline{\text{PE1-4}}$ , or CE1N High During MOVX	t <sub>CEHDA</sub>	4t <sub>CLK</sub> -30		ns
46	Delay from Bytewide Address Valid $\overline{\text{CE1-4}}$ , $\overline{\text{PE1-4}}$ , or CE1N Low During MOVX	t <sub>CELDA</sub>	4t <sub>CLK</sub> -35		ns
47	Bytewide Data Setup to $\overline{\text{CE1-4}}$ , $\overline{\text{PE1-4}}$ , or CE1N High During MOVX (read)	t <sub>DACEH</sub>	1t <sub>CLK</sub> +40		ns
48	Bytewide Data Hold After $\overline{\text{CE1-4}}$ , $\overline{\text{PE1-4}}$ , or CE1N High During MOVX (read)	t <sub>CEHDV</sub>	10		ns
49	Bytewide Address Valid to R/W Active During MOVX (write)	t <sub>AVRWL</sub>	3t <sub>CLK</sub> -35		ns
50	Delay from R/W Low to Valid Data Out During MOVX (write)	t <sub>RWLDV</sub>	20		ns
51	Valid Data Out Hold Time from $\overline{\text{CE1-4}}$ , $\overline{\text{PE1-4}}$ , or CE1N High	t <sub>CEHDV</sub>	1t <sub>CLK</sub> -15		ns
52	Valid Data Out Hold Time from R/W High	t <sub>RWHDV</sub>	0		ns
53	Write Pulse Width (R/W Low Time)	t <sub>RWLPW</sub>	6t <sub>CLK</sub> -20		ns

# DALLAS SEMICONDUCTOR CORP

## BYTEWIDE BUS TIMING



### RPC AC CHARACTERISTICS - DBB READ

( $t_A = 0^\circ\text{C to } 70^\circ\text{C}$ ;  $V_{CC} = 5V \pm 10\%$ )

#	PARAMETER	SYMBOL	MIN	MAX	UNITS
54	$\overline{CS}$ , $A_0$ Setup to $\overline{RD}$	$t_{AR}$	0		ns
55	$\overline{CS}$ , $A_0$ Hold After $\overline{RD}$	$t_{RA}$	0		ns
56	$\overline{RD}$ Pulse Width	$t_{RR}$	160		ns
57	$\overline{CS}$ , $A_0$ to Data Out Delay	$t_{AD}$		130	ns
58	$\overline{RD}$ to Data Out Delay	$t_{RD}$	0	130	ns
59	$\overline{RD}$ to Data Float Delay	$t_{RDZ}$		85	ns



**RPC AC CHARACTERISTICS – DBB WRITE** $(t_A = 0^\circ\text{C to } 70^\circ\text{C}; V_{CC} = 5V \pm 10\%)$ 

#	PARAMETER	SYMBOL	MIN	MAX	UNITS
60	$\overline{CS}$ , $A_0$ Setup to $\overline{WR}$	$t_{AW}$	0		ns
61A	$\overline{CS}$ , Hold After $\overline{WR}$	$t_{WA}$	0		ns
61B	$A_0$ , Hold After $\overline{WR}$	$t_{WA}$	20		ns
62	$\overline{WR}$ Pulse Width	$t_{WW}$	160		ns
63	Data Setup to $\overline{WR}$	$t_{DW}$	130		ns
64	Data Hold After $\overline{WR}$	$t_{WD}$	20		ns

**AC CHARACTERISTICS – DMA** $(t_A = 0^\circ\text{C to } 70^\circ\text{C}; V_{CC} = 5V \pm 10\%)$ 

#	PARAMETER	SYMBOL	MIN	MAX	UNITS
65	$\overline{DACK}$ to $\overline{WR}$ or $\overline{RD}$	$t_{ACC}$	0		ns
66	$\overline{RD}$ or $\overline{WR}$ to $\overline{DACK}$	$t_{CAC}$	0		ns
67	$\overline{DACK}$ to Data Valid	$t_{ACD}$	0	130	ns
68	$\overline{RD}$ or $\overline{WR}$ to $\overline{DRQ}$ Cleared	$t_{CRQ}$		110	ns

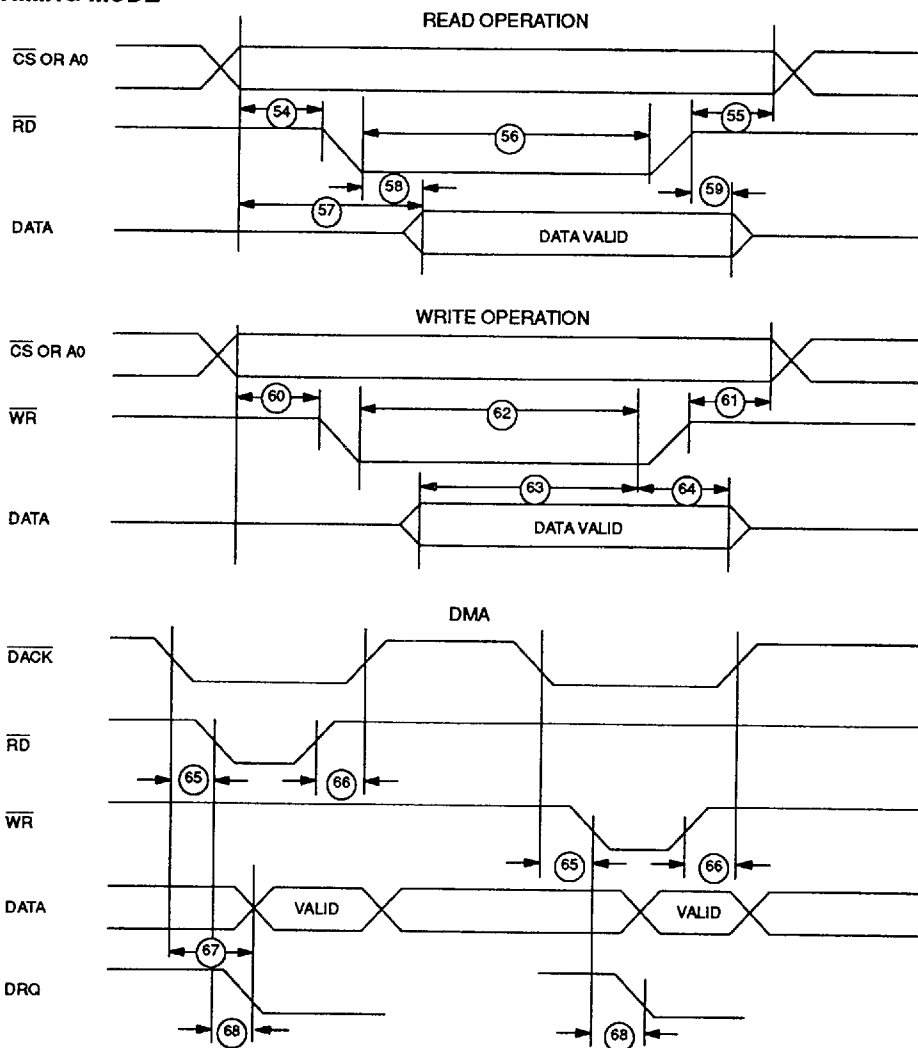
**AC CHARACTERISTICS – PROG** $(t_A = 0^\circ\text{C to } 70^\circ\text{C}; V_{CC} = 5V \pm 10\%)$ 

#	PARAMETER	SYMBOL	MIN	MAX	UNITS
69	$\overline{PROG}$ Low to Active	$t_{PRA}$	48		CLKS
70	$\overline{PROG}$ High to Inactive	$t_{PRI}$	48		CLKS

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## RPC TIMING MODE

## DALLAS SEMICONDUCTOR CORP



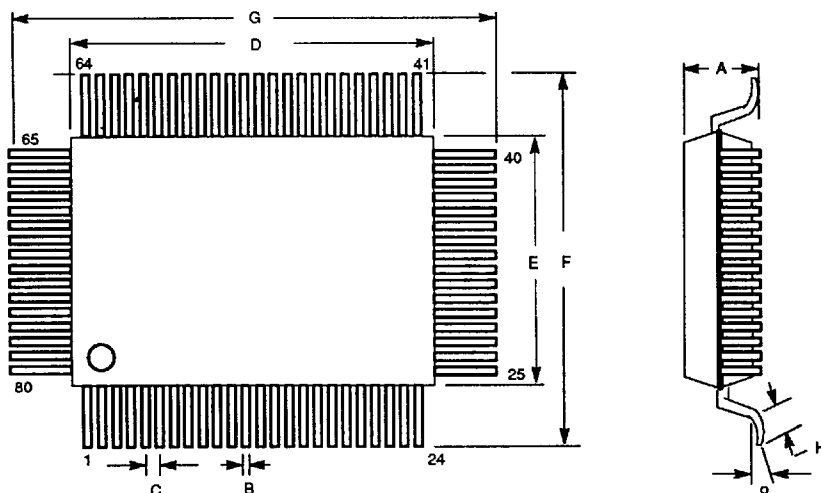
## NOTES:

1. All voltages are referenced to ground.
2. Maximum operating  $I_{CC}$  is measured with all output pins disconnected; XTAL1 driven with  $t_{CLKR}$ ,  $t_{CLKF}=10$  ns,  $V_{IL}=0.5$  V; XTAL2 disconnected; RST = PORT0 =  $V_{CC}$ , MSEL =  $V_{SS}$ .
3. Idle mode  $I_{IDLE}$  is measured with all output pins disconnected; XTAL1 driven with  $t_{CLKR}$ ,  $t_{CLKF}=10$  ns,  $V_{IL}=0.5$  V; XTAL2 disconnected; PORT0 =  $V_{CC}$ , RST = MSEL =  $V_{SS}$ .
4. Stop mode  $I_{STOP}$  is measured with all output pins disconnected; PORT0 =  $V_{CC}$ ; XTAL2 not connected; RST = MSEL = XTAL1 =  $V_{SS}$ .
5. Pin Capacitance is measured with a test frequency – 1 MHz,  $t_A=25^\circ\text{C}$ .

## DALLAS SEMICONDUCTOR CORP

6.  $I_{CCO1}$  is the maximum average operating current that can be drawn from  $V_{CCO}$  in normal operation.
7.  $I_{LI}$  is the current drawn from  $V_{LI}$  input when  $V_{CC} = 0V$  and  $V_{CCO}$  is disconnected. Battery-backed mode:  $2.5V \leq V_{BAT} \leq 4.0$ ;  $V_{CC} \leq V_{BAT}$ ;  $V_{SDI}$  should be  $\leq V_{ILS}$  for  $I_{BAT}$  max.
8.  $V_{CCO2}$  is measured with  $V_{CC} < V_{LI}$ , and a maximum load of  $10 \mu A$  on  $V_{CCO}$ .
9. Crystal start-up time is the time required to get the mass of the crystal into vibrational motion from the time that power is first applied to the circuit until the first clock pulse is produced by the on-chip oscillator. The user should check with the crystal vendor for a worst case specification on this time.
10. SDI is deglitched to prevent accidental destruction. The pulse must be longer than  $t_{SPR}$  to pass the deglitcher, but SDI is not guaranteed unless it is longer than  $t_{SPA}$ .

## DS5002FP CMOS MICROCONTROLLER



DIM	MILLIMETERS		
	MIN	NOM	MAX
A	—	2.91	3.15
B	0.25	0.35	0.45
C	—	0.80	—
D	19.85	20.00	20.15
E	13.85	14.00	14.15
F	17.40	17.86	18.20
G	23.40	23.86	24.20
H	0.40	—	1.3
I	0	—	10°